

## 650V GaN Power Transistor ( FET )

### Features

- \*  $V_{DS}=650V$ ,  $I_D=9A$
- \* Easy to use, compatible with standard gate drivers
- \* Excellent  $Q_g \times R_{DS(on)}$  figure of merit (FOM)
- \* Low  $Q_{rr}$ , No free-wheeling diode required
- \* Low Switching Loss
- \* Lead Free Available(RoHS Compliant)
- \* DFN-8X8-3L Packages

### Applications

- \* High Efficiency Power Supplies
- \* High Efficiency USB PD Adapters
- \* Other Consumer Electronics

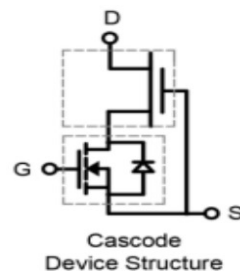
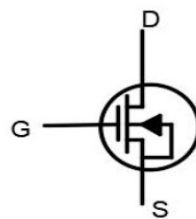
### Product Summary

$V_{DS}$	650	V
$R_{DS(on)}$ , Typ.	240	mΩ
$Q_g$ , Typ.	21.5	nC
$Q_{RR}$ , Typ.	39	nC

### Pin Description and Schematic



DFN-8X8-3L



### Package Marking And Ordering Information

Device	Marking	Device Package	Quantity
SWGN9N65DN3L/TR	GN9N65DN3	DFN-8X8-3L	2500pcs, Tape&Reel

### ABSOLUTE MAXIMUM RATINGS ( $T_j = 25^{\circ}C$ UNLESS OTHERWISE NOTED)

Parameter		Symbol	SWGN9N65DN	Unit
Drain to Source Voltage ( $T_j=-55^{\circ}C$ to $150^{\circ}C$ )		$V_{DS}$	650	V
Gate to Source Voltage		$V_{GS}$	$\pm 20$	V
Coutinuous Drain Current	$T_c=25^{\circ}C$	$I_D$	9	A
	$T_c=100^{\circ}C$		6	A
Pulsed Drain Current (pulse width:10us)	$T_c=25^{\circ}C$	$I_{DM}$	31	A
	$T_c=150^{\circ}C$		23	
Maximum Power Dissipation	$T_c=25^{\circ}C$	$P_D$	38	W
Operating Junction and Storage Temperature Range		$T_J, T_{stg}$	-55 to 150	$^{\circ}C$
Soldering Peak Temperature		$T_{CSOLD}$	260	$^{\circ}C$
Thermal Resistance, Junction-to-Case(Maximum)		$R_{QJC}$	3.3	$^{\circ}C/W$
Thermal Resistance, Junction-to-Ambient(Maximum) <sup>note2</sup>		$R_{QJA}$	50	$^{\circ}C/W$

Note 1. Device on one layer epoxy PCB for drain connection(vertical and without air stream cooling  
with 6cm<sup>2</sup> copper area and 70um thickness)

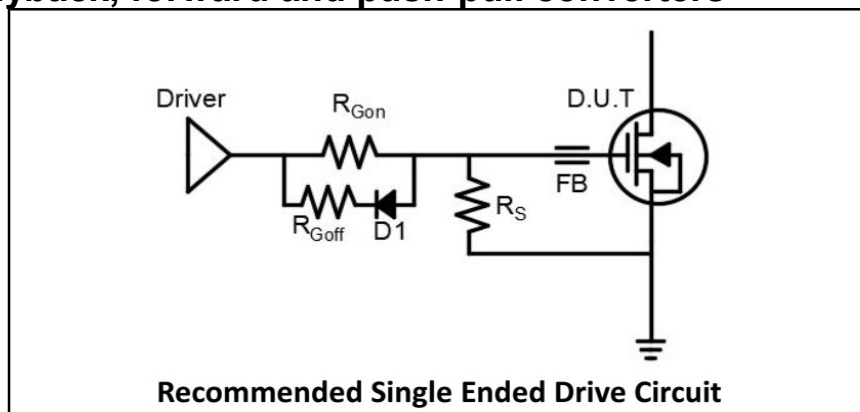
**Electrical Characteristics** (TA = 25°C unless otherwise noted)

Parameter	Symbol	Test Conditions	SWGN9N65DN			Unit
			Min	Typ	Max	
Forward Device Characteristics						
Drain -Source Breakdown Voltage	VDSS-MAX	VGS=0V,	650	-	-	V
Zero Gate Voltage Drain Current	IDSS	VDS=700V, VGS=0V, TJ=25'C	-	8	20	uA
Zero Gate Voltage Drain Current	IDSS	VDS=700V, VGS=0V, TJ=100'C	-	50	-	
Gate-Body Leakage Current	IGSS	VDS=0V, VGS= ±20V	-	-	±150	nA
Gate-Threshold Voltage	VGS(th)	VGS = VDS, ID= 500uA	1.2	1.6	2.0	V
Drain-Source-On-Resistance <sup>note4</sup>	RDS(on)	VGS=8V, IDS=4A, TJ=25'C	190	240	290	mΩ
		VGS=8V, IDS=4A, TJ=150'C	-	500	-	mΩ
Dynamic Characteristics						
Input Capacitance	CISS	VDS= 650V, VGS= 0V F=1MHz	-	500	-	pF
Output Capacitance	COSS		-	18	-	
Reverse Transfer Capacitance	CRSS		-	2	-	
Output Capacitance(er)	CO(er)	VDS= 0-650V, VGS= 0V	-	25	-	pF
Output Capacitance(tr)	CO(tr)		-	45	-	
Turn-On Delay Time	td(ON)	VDS=400V,IDS=3A, VGS=0-12V, RG=30Ω	-	20	-	ns
Rise Time	tr		-	7	-	ns
Turn-Off Delay Time	td(OFF)		-	80	-	ns
Fall Time	tf		-	6	-	ns
Gate Charge Characteristics						
Total Gate Charge	Qg	VDS= 400V, VGS= 0-12V IDS=5.5A	-	21.5	-	nC
Gate-Source Charge	Qgs		-	3.0	-	
Gate-Drain Charge	Qgd		-	3.5	-	
Reverse Diode Characteristics						
Diodes Forward Voltage <sup>note4</sup>	VSD	VGS=0V, IDS=2A, TJ=25'C	-	1.2	-	V
		VGS=0V, IDS=5A, TJ=25'C	-	1.7	-	V
		VGS=0V, IDS=5A, TJ=150'C	-	2.0	-	V
Reverse Recovery Time	trr	Is=3A, VGS=0V, VDD=400V, di/dt=1000A/us(Note3)	-	12	-	nS
Reverse Recovery Charge	Qrr		-	39	-	uC

Note 4. Dynamic on-resistance;

## Circuit Implementation

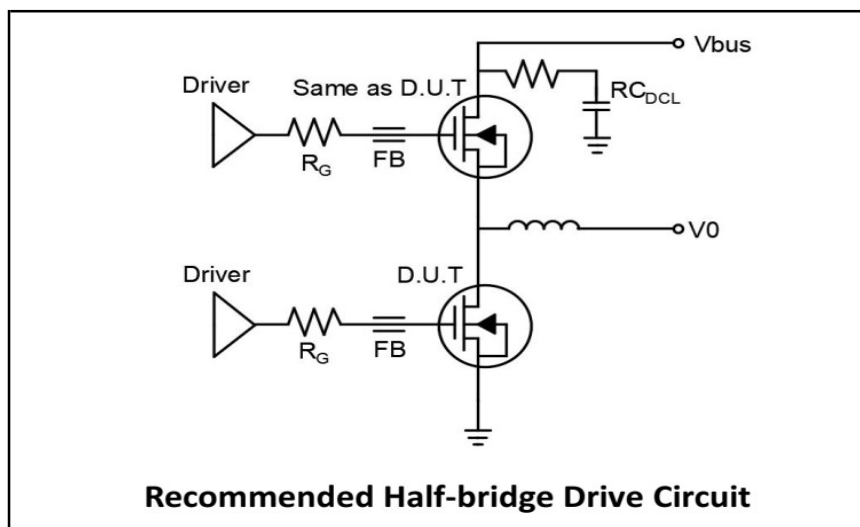
Mostly used in flyback, forward and push-pull converters



Recommended gate drive: (0V, 12V) with  $R_{Gon}=300 - 500\Omega$ ,  $R_{Goff}=10\Omega$

Gate Ferrite Bead (FB)	Gate Resistance ( $R_{Gon}$ )	Gate Resistance ( $R_{Goff}$ )	Gate Source Resistance ( $R_S$ )	Gate Diode (D1)
300-600 $\Omega$ @100MHz	300-500 $\Omega$	10 $\Omega$	10K $\Omega$	1N4148

Mostly used in half bridge and full bridge topology



Recommended gate drive: (0V, 12V) with  $R_G=30 - 70\Omega$

Gate Ferrite Bead ( FB )	Gate Resistance ( $R_G$ )	DC Link RC Snubber ( $RC_{DCL}$ )
300 $\Omega$ @100MHz	30 - 70 $\Omega$	4nF + 2 $\Omega$

Notes:

- $RC_{DCL}$  should be placed as close as possible to the drain pin.
- The layout and wiring of the drive circuit should be as short as possible.

Typical Characteristics ( $T_J = 25^\circ\text{C}$  unless otherwise noted)

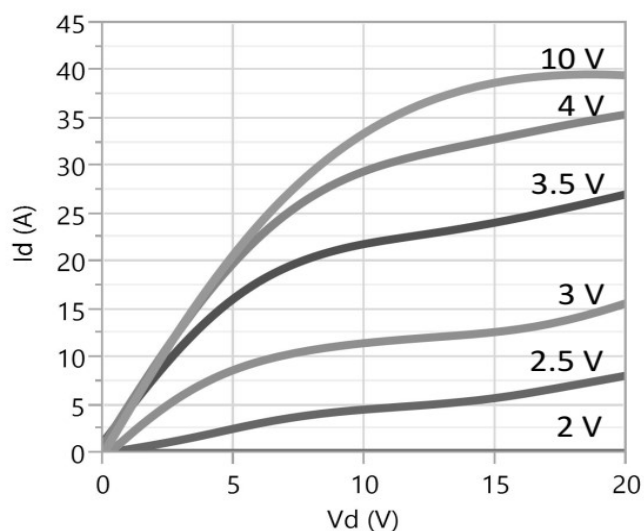


Figure 1: Typical Output Characteristics

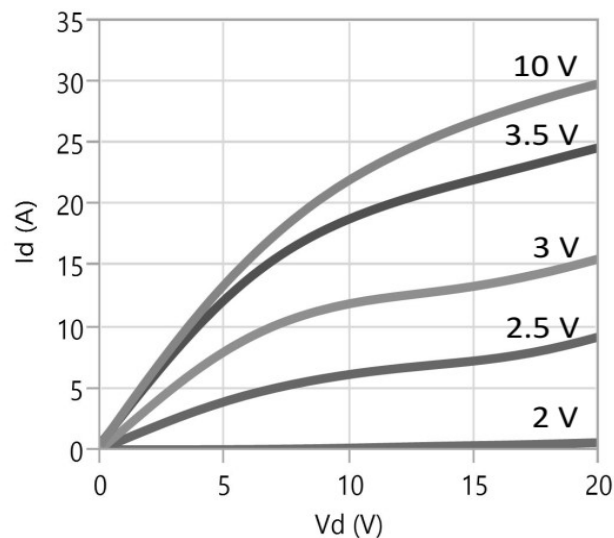


Figure 2: Typical Output Characteristics  $T_J = 150^\circ\text{C}$

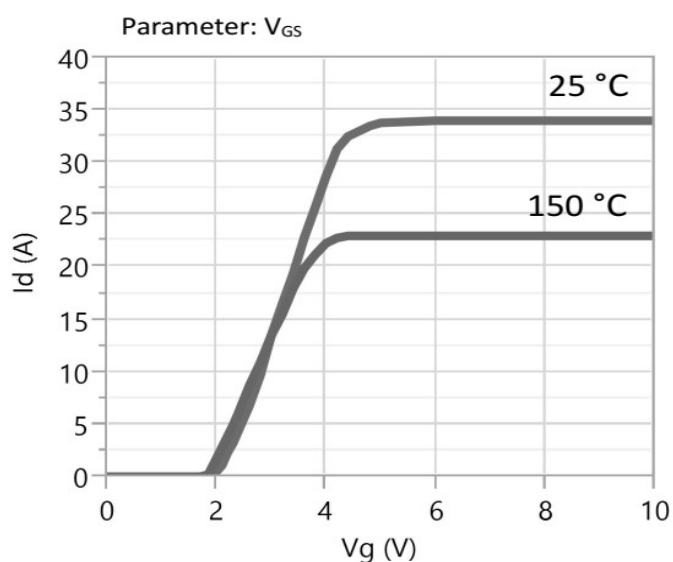


Figure 3: Typical Transfer Characteristics

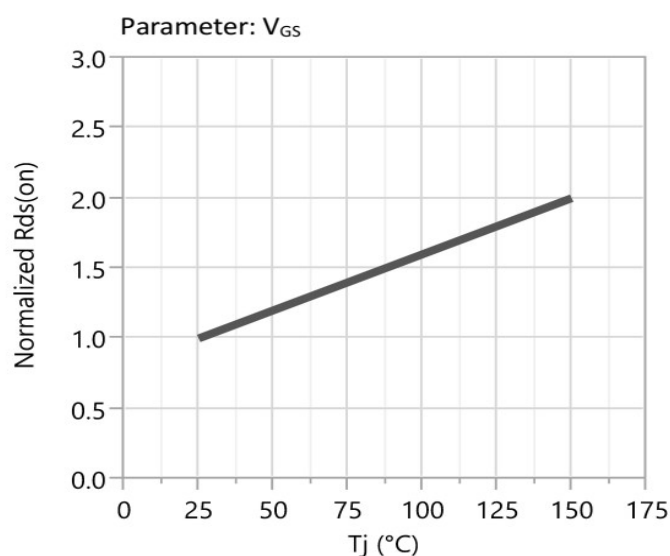


Figure 4: Normalized On-resistance

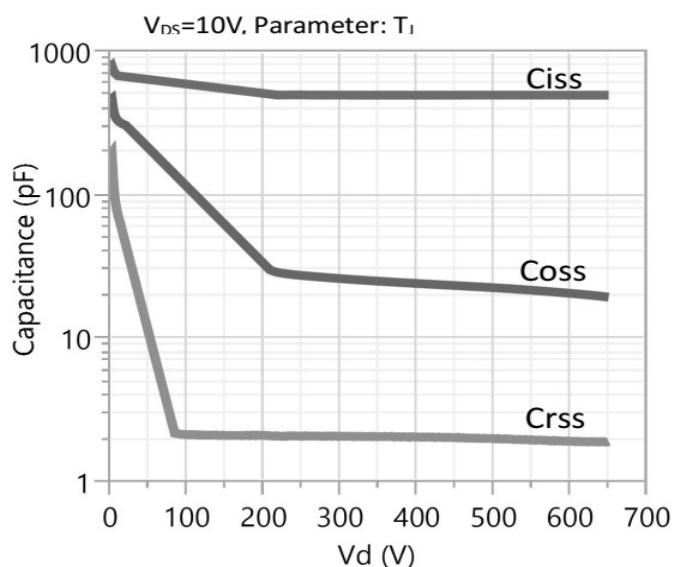


Figure 5: Typical Capacitance ( $V_{GS} = 0\text{V}$ ,  $f = 1\text{MHz}$ )

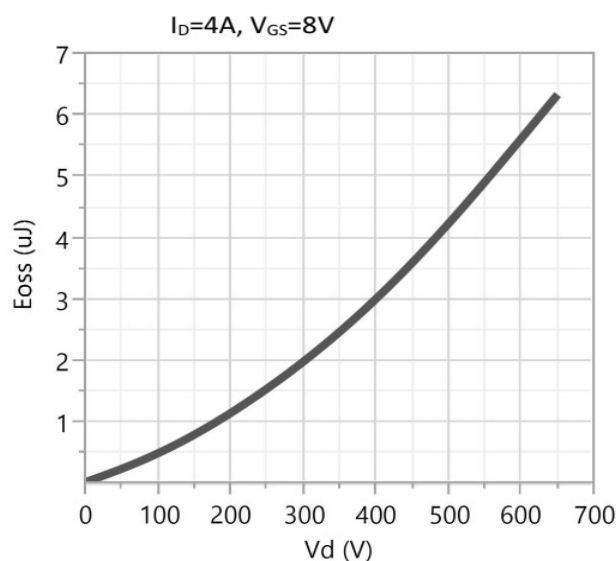


Figure 6: Typical  $C_{oss}$  Stored Energy

Typical Characteristics (T<sub>J</sub> = 25°C unless otherwise noted)(Con.)

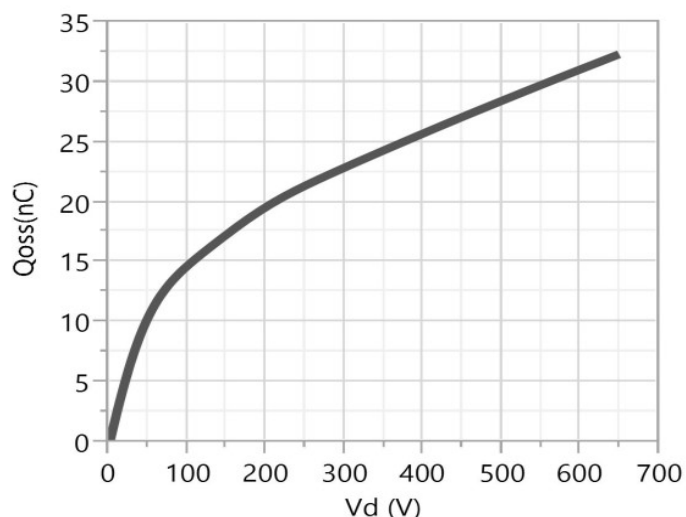


Figure 7: Typical Qoss

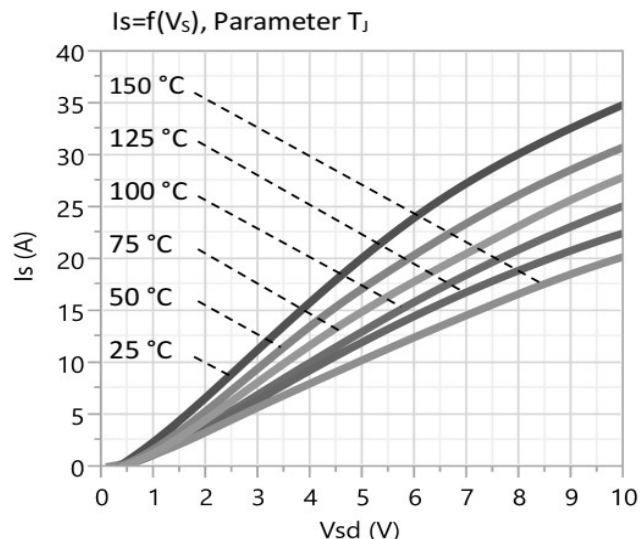


Figure 8: Forward Characteristic of Rev. Diode

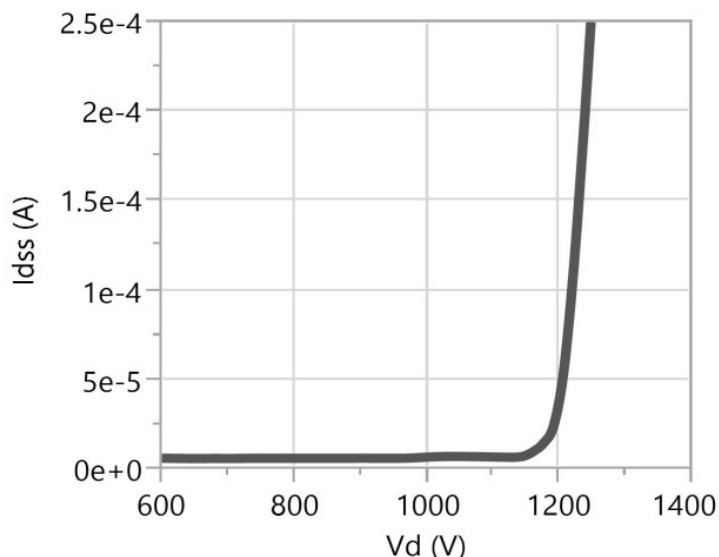


Figure 9: Drain-Source Breakdown Voltage

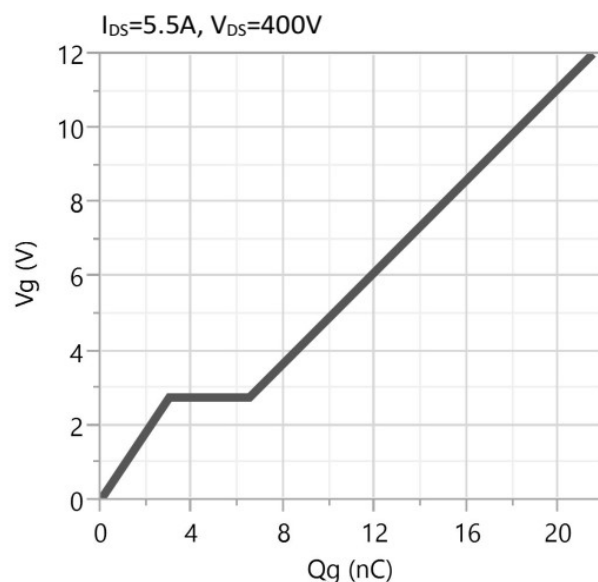


Figure 10: Typical Gate Charge

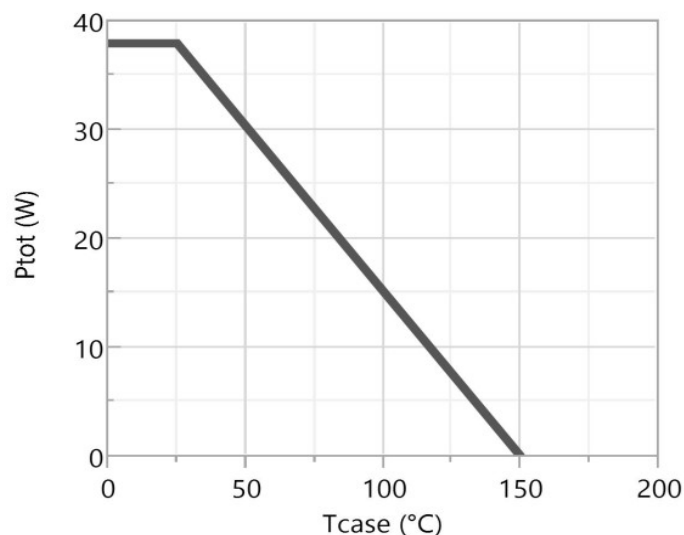


Figure 11: Power Dissipation

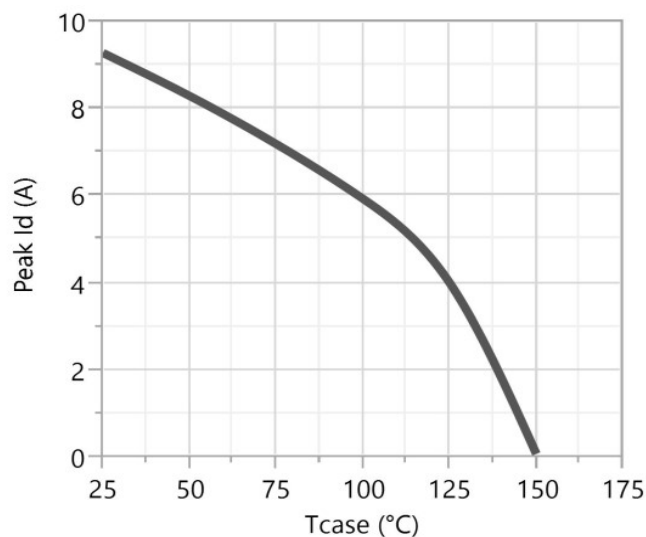


Figure 12: Current Derating

Typical Characteristics (T<sub>J</sub> = 25°C unless otherwise noted)(Con.)

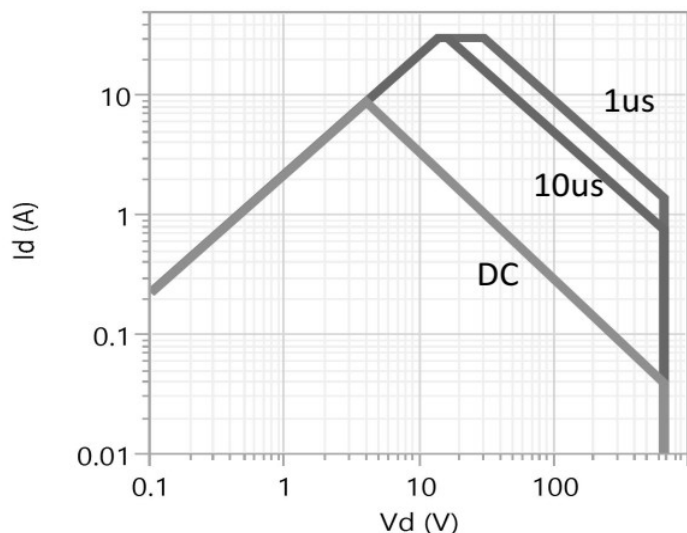


Figure 13: Safe Operating Area T<sub>c</sub>=25°C

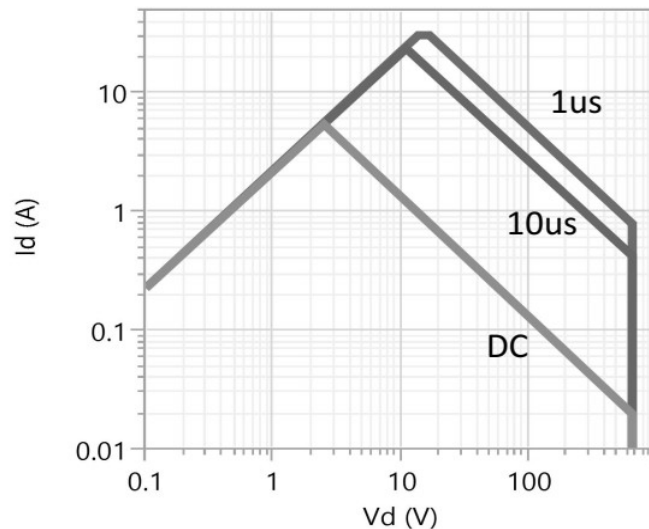


Figure 14: Safe Operating Area T<sub>c</sub>=80°C

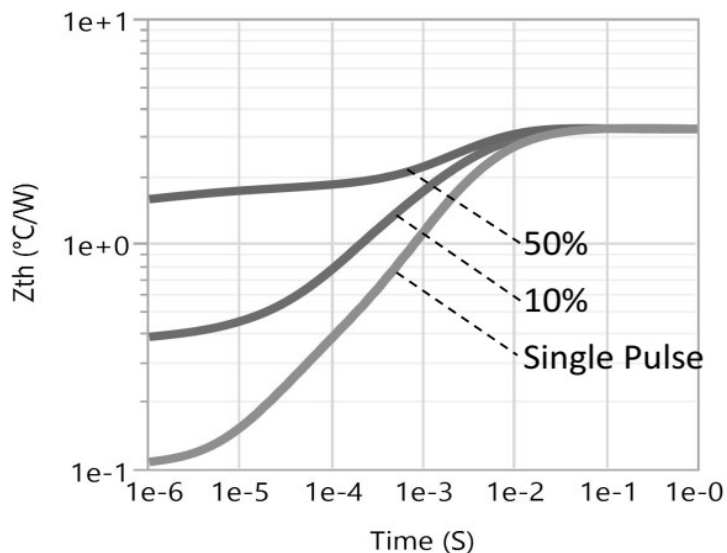
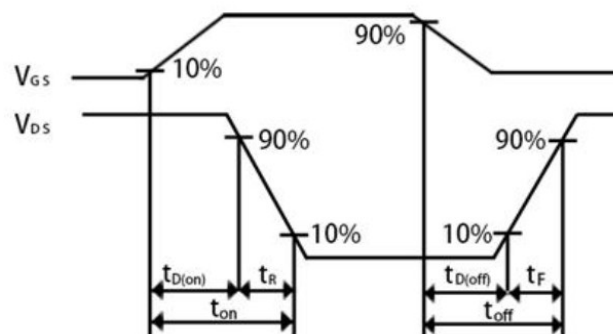
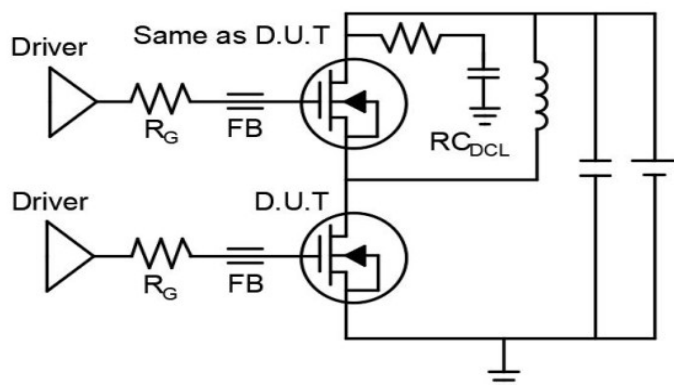


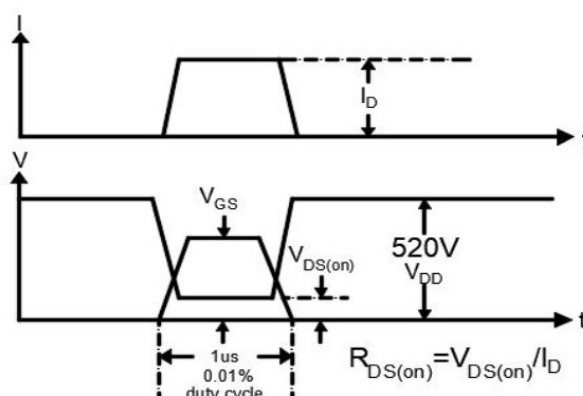
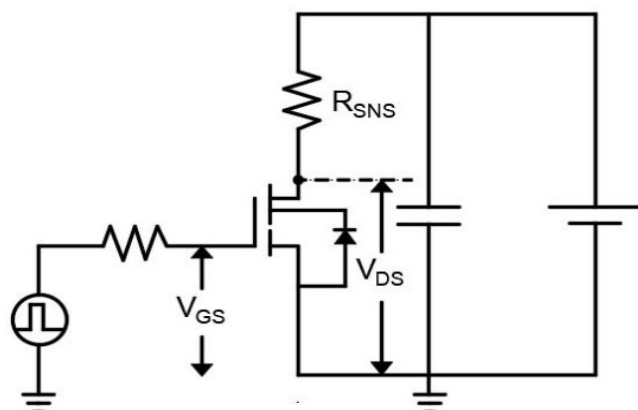
Figure 15: Transient Thermal Resistance

## Test Circuit and Waveforms

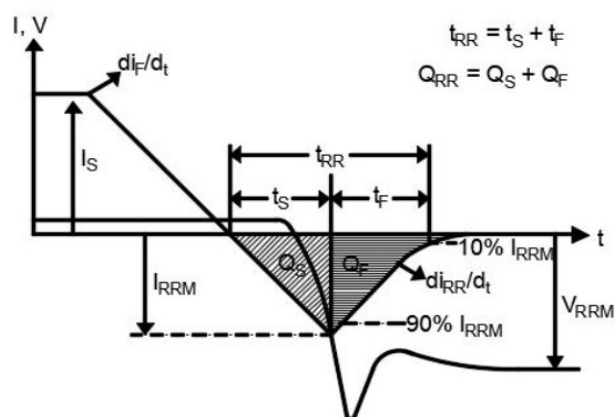
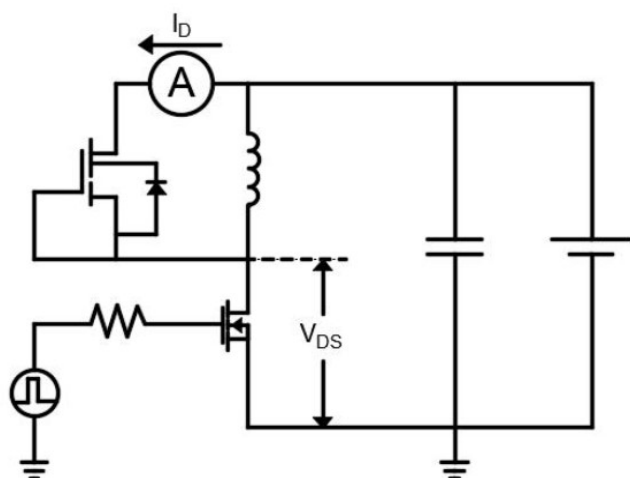
### Switching Time Test Circuit and Waveform



### Dynamic $R_{DS(on)}$ Test Circuit and Waveform



### Diode Characteristic Test Circuits and Waveform





## Design Guidelines

Fast switching GaN device can reduce power conversion losses, and thus enable high frequency operations. Certain PCB design rules and instructions, however, need to be followed to take full advantages of fast switching GaN devices.

Before evaluating Star-wing's GaN devices, please refer to the table below which provides some practical rules that should be followed during the evaluation.

When Evaluating Star-wing's GaN Devices:

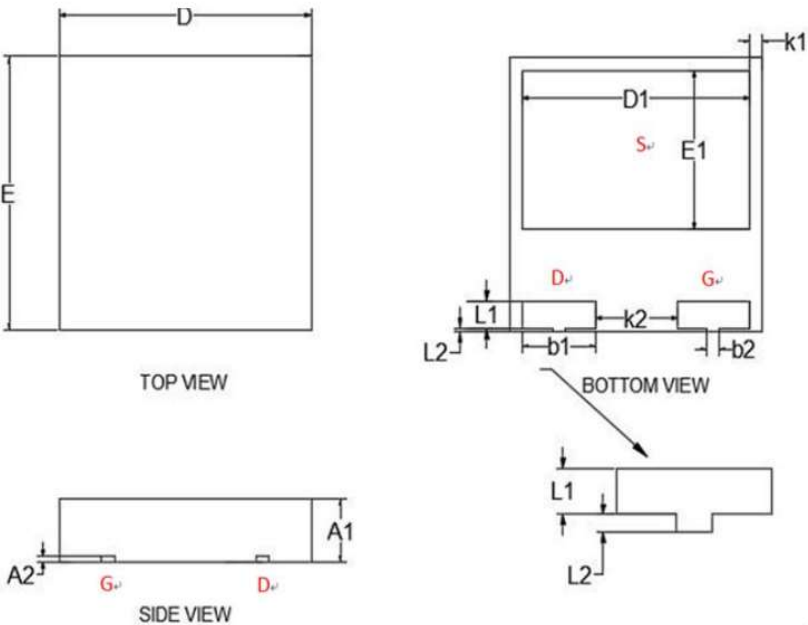
DO	DO NOT
Make sure the traces are as short as possible for both drive and power loops to minimize parasitic inductance	Using Star-wing devices in GDS board layouts
Use the test tool with the shortest inductive loop, and make sure test points should be placed close enough	Use differential mode probe or probe ground clip with long wires
Minimize the lead length of DFN-8X8-3L packages when installing them to PCB	Use long traces in drive circuit, or long lead length of the devices



Packaging Information

PKG: DFN-8X8-3L Package

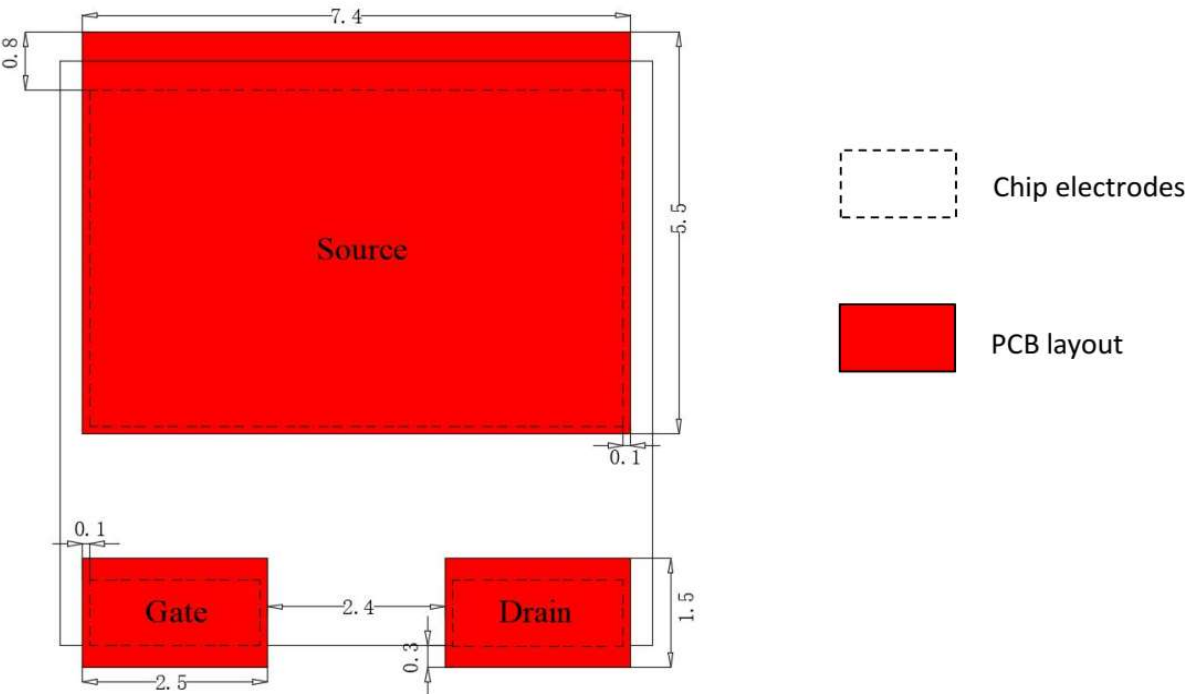
unit : mm



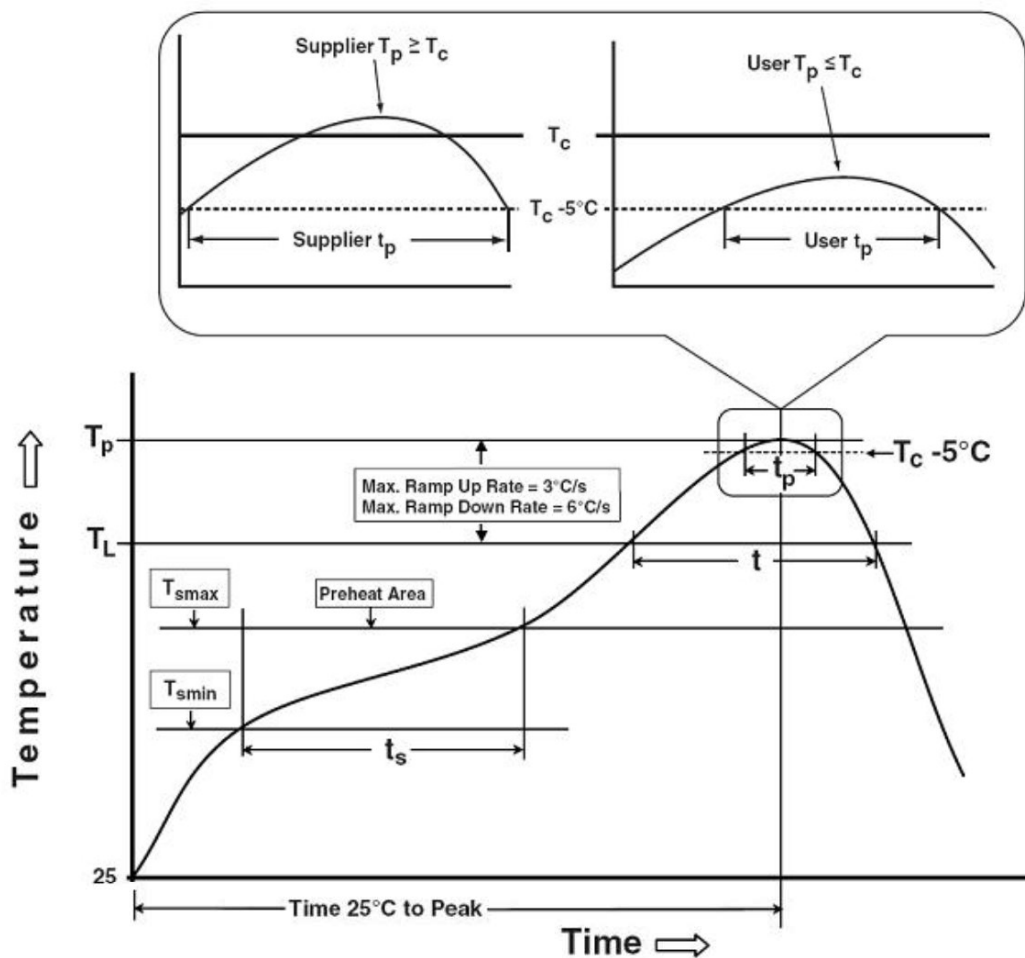
Symbol	Dimensions in Millimeters		
	MIN	NOM	MAX
A1	1.750	1.850	1.950
A2	0.185	0.203	0.230
D	7.000	8.000	9.000
E	7.950	8.000	8.050
D1	7.050	7.200	7.350
E1	4.450	4.600	4.750
K1	0.375	0.400	0.425
K2	2.575	2.600	2.625
b1	2.250	2.300	2.350
b2	0.375	0.400	0.425
L1	0.700	0.800	0.900
L2	0.075	0.100	0.125

Recommended PCB Layout

Dimensions are shown in millimeters



## Classification Profile



## Classification Reflow Profiles

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
<b>Preheat &amp; Soak</b>		
Temperature min ( $T_{smin}$ )	100 °C	150 °C
Temperature max ( $T_{smax}$ )	150 °C	200 °C
Time ( $T_{smin}$ to $T_{smax}$ ) ( $t_s$ )	60-120 seconds	60-120 seconds
Average ramp-up rate ( $T_{smax}$ to $T_p$ )	3 °C/second max.	3°C/second max.
Liquidous temperature ( $T_L$ )	183 °C	217 °C
Time at liquidous ( $t_L$ )	60-150 seconds	60-150 seconds
Peak package body Temperature ( $T_p$ )*	See Classification Temp in table 1	See Classification Temp in table 2
Time ( $t_p$ )** within 5°C of the specified classification temperature ( $T_c$ )	20** seconds	30** seconds
Average ramp-down rate ( $T_p$ to $T_{smax}$ )	6 °C/second max.	6 °C/second max.
Time 25°C to peak temperature	6 minutes max.	8 minutes max.
*Tolerance for peak profile Temperature ( $T_p$ ) is defined as a supplier minimum and a user maximum.		
** Tolerance for time at peak profile temperature ( $t_p$ ) is defined as a supplier minimum and a user maximum.		

Table 1.SnPb Eutectic Process – Classification Temperatures (Tc)

<b>Package Thickness</b>	<b>Volume mm<sup>3</sup> &lt;350</b>	<b>Volume mm<sup>3</sup> ≥350</b>
<2.5 mm	235 °C	220 °C
≥2.5 mm	220 °C	220 °C

Table 2.Pb-free Process – Classification Temperatures (Tc)

<b>Package Thickness</b>	<b>Volume mm<sup>3</sup> &lt;350</b>	<b>Volume mm<sup>3</sup> 350-2000</b>	<b>Volume mm<sup>3</sup> ≥2000</b>
<1.6 mm	260 °C	260 °C	260 °C
1.6 mm – 2.5 mm	260 °C	250 °C	245 °C
≥2.5 mm	250 °C	245 °C	245 °C

## Reliability Test Program

<b>Test item</b>	<b>Method</b>	<b>Description</b>
SOLDERABILITY	JESD-22, B102	5 Sec, 245°C
PRECON	JESD-22, A113	30°C/60%/192Hrs
HTRB	JESD-22, A108	168/500/1000 Hrs, Bias @ 150°C
HTGB	JESD-22, A108	168 /500/1000Hrs, V <sub>gs</sub> 100% @ 150°C
PCT	JESD-22, A102	96 Hrs, 100%RH, 2atm, 121°C
TCT	JESD-22, A104	500 Cycles, -55°C~150°C